

ON Semiconductor®

FDT439N

N-Channel 2.5V Specified Enhancement Mode Field Effect Transistor

General Description

This N-Channel Enhancement mode field effect transistor is produced using Fairchild Semiconductor's proprietary, high cell density, DMOS technology. This very high density process is especially tailored to minimize onstate resistance, and provide superior switching performance. These products are well suited to low voltage, low current applications such as notebook computer power management, battery powered circuits, and DC motor control.

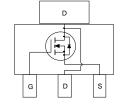
Features

- 6.3 A, 30 V. $R_{DS(on)} = 0.045 \ \Omega \ @V_{GS} = 4.5 \ V$ $R_{DS(on)} = 0.058 \ \Omega \ @V_{GS} = 2.5 \ V$
- Fast switching speed.
- High power and current handling capabitlity in a widely used surface mount package.

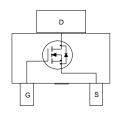
Applications

- DC/DC converter
- · Load switch
- Motor driving









Absolute Maximum Ratings T_A = 25°C unless otherwise noted

Symbol	Parameter		FDT439N	Units
V _{DSS}	Drain-Source Voltage		30	V
V _{GSS}	Gate-Source Voltage		<u>+</u> 8	V
I _D	Drain Current - Continuous	(Note 1a)	6.3	Α
	- Pulsed		20	
P _D	P _D Power Dissipation for Single Operation		3	W
		(Note 1b)	1.3	
		(Note 1c)	1.1	
T _J , T _{stg}	Operating and Storage Junction Temperature Range		-55 to +150	∘C

Thermal Characteristics

$R_{\theta^{JA}}$	Thermal Resistance, Junction-to-Ambient	(Note 1a)	42	°C/W
R _{AJC}	Thermal Resistance, Junction-to-Case	(Note 1)	12	∘C/W

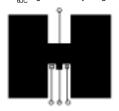
Package Marking and Ordering Information

-	r dorlago marking and ordornig information					
	Device Marking	Device	Reel Size	Tape Width	Quantity	_
	FDT439N	FDT439N	13"	12mm	2500 units	

Symbol	Parameter	Test Conditions		Тур	Max	Units
Off Char	acteristics					
BV _{DSS}	Drain-Source Breakdown Voltage	$V_{GS} = 0 \text{ V}, I_{D} = 250 \mu\text{A}$	30			V
ΔBV _{DSS} ΔT _J	Breakdown Voltage Temperature Coefficient	I _D = 250 μA, Referenced to 25°C		40		mV/°C
I _{DSS}	Zero Gate Voltage Drain Current	V _{DS} = 24 V, V _{GS} = 0 V			1	μΑ
I _{GSSF}	Gate-Body Leakage Current, Forward	V _{GS} = 8 V, V _{DS} = 0 V			100	nA
I _{GSSR}	Gate-Body Leakage Current, Reverse	V _{GS} = -8 V, V _{DS} = 0 V			-100	nA
On Char	acteristics (Note 2)			•		
V _{GS(th)}	Gate Threshold Voltage	$V_{DS} = V_{GS}, I_{D} = 250 \mu\text{A}$	0.4	0.67	1	V
$\frac{\Delta V_{GS(th)}}{\Delta T_J}$	Gate Threshold Voltage Temperature Coefficient	I _D = 250 μA, Referenced to 25°C		-2.2		mV/°C
R _{DS(on)}	Static Drain-Source On-Resistance	$V_{GS} = 4.5 \text{ V}, I_D = 6.3 \text{ A}$ $V_{GS} = 4.5 \text{ V}, I_D = 6.3 \text{ A}, T_J = 125^{\circ}\text{C}$ $V_{GS} = 2.5 \text{ V}, I_D = 5.5 \text{A}$		0.038 0.055 0.048	0.045 0.072 0.058	Ω
I _{D(on)}	On-State Drain Current	V _{GS} = 4.5 V, V _{DS} = 5 V	10			Α
g FS	Forward Transconductance	V _{DS} = 5 V, I _D = 6.3 A		17		S
Dvnamic	Characteristics					
Ciss	Input Capacitance	V _{DS} = 15 V, V _{GS} = 0 V,		500		pF
Coss	Output Capacitance	f = 1.0 MHz		185		pF
C _{rss}	Reverse Transfer Capacitance			43		pF
Switchin	ng Characteristics (Note 2)					
t _{d(on)}	Turn-On Delay Time	V _{DD} = 15 V, I _D = 1 A,		6	12	ns
t _r	Turn-On Rise Time	$V_{GS} = 4.5 \text{ V}, R_{GEN} = 6 \Omega$		10	18	ns
t _{d(off)}	Turn-Off Delay Time			30	48	ns
t _f	Turn-Off Fall Time			10	18	ns
Qg	Total Gate Charge	$V_{DS} = 15 \text{ V}, I_D = 6.3 \text{ A},$		10.7	15	nC
Q _{gs}	Gate-Source Charge	$V_{GS} = 4.5 V$,		0.9		nC
Q _{gd}	Gate-Drain Charge			3.7		nC
Drain-Sc	ource Diode Characteristics and	d Maximum Ratings				
Is	Maximum Continuous Drain-Source Did				2.5	Α
V _{SD}	Drain-Source Diode Forward Voltage	$V_{GS} = 0 \text{ V}, I_{S} = 2.5 \text{ A}$ (Note 2)		0.8	1.2	V

Notes

^{1.} $R_{\theta JA}$ is the sum of the junction-to-case and case-to-ambient thermal resistance where the case thermal reference is defined as the solder mounting surface of the drain pins. $R_{\theta JC}$ is guaranteed by design while $R_{\theta CA}$ is determined by the user's board design.



a) 42° C/W when mounted on a 1 in² pad of 2 oz. copper.



b) 95° C/W when mounted on a 0.066 in² pad of 2 oz. copper.



c) 110° C/W when mounted on a minimum mounting pad.

Scale 1 : 1 on letter size paper

2. Pulse Test: Pulse Width \leq 300 μ s, Duty Cycle \leq 2.0%

Typical Characteristics

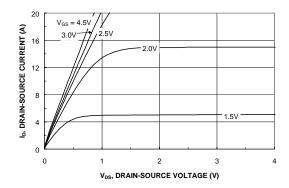


Figure 1. On-Region Characteristics.

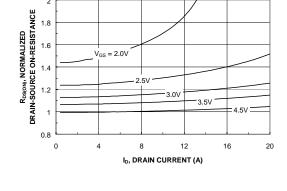


Figure 2. On-Resistance Variation with Drain Current and Gate Voltage.

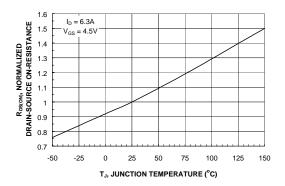


Figure 3. On-Resistance Variation with Temperature.

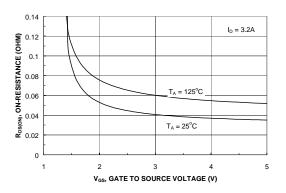


Figure 4. On-Resistance Variation with Gate-To-Source Voltage.

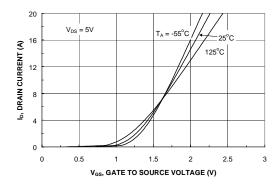


Figure 5. Transfer Characteristics.

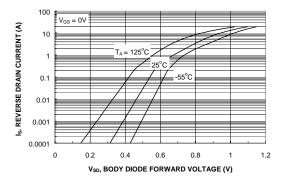
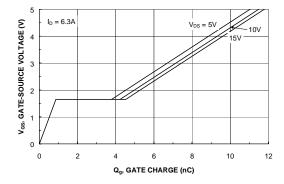


Figure 6. Body Diode Forward Voltage Variation with Source Current and Temperature.

Typical Characteristics (continued)



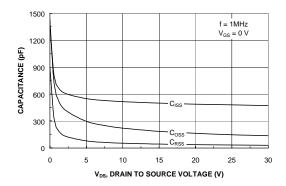
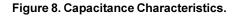
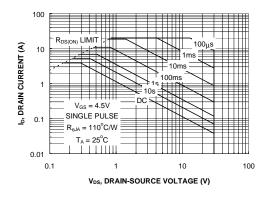


Figure 7. Gate-Charge Characteristics.





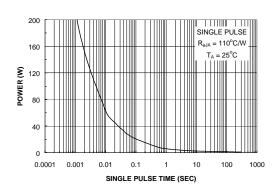


Figure 9. Maximum Safe Operating Area.

Figure 10. Single Pulse Maximum Power Dissipation.

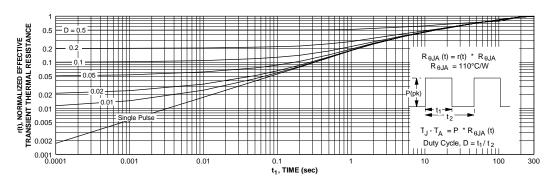


Figure 11. Transient Thermal Response Curve.

Thermal characterization performed using the conditions described in Note 1. Transient themal response will change depending on the circuit board design.

ON Semiconductor and in are trademarks of Semiconductor Components Industries, LLC dba ON Semiconductor or its subsidiaries in the United States and/or other countries. ON Semiconductor owns the rights to a number of patents, trademarks, copyrights, trade secrets, and other intellectual property. A listing of ON Semiconductor's product/patent coverage may be accessed at www.onsemi.com/site/pdf/Patent-Marking.pdf. ON Semiconductor reserves the right to make changes without further notice to any products herein. ON Semiconductor makes no warranty, representation or guarantee regarding the suitability of its products for any particular purpose, nor does ON Semiconductor assume any liability arising out of the application or use of any product or circuit, and specifically disclaims any and all liability, including without limitation special, consequential or incidental damages. Buyer is responsible for its products and applications using ON Semiconductor products, including compliance with all laws, regulations and safety requirements or standards, regardless of any support or applications information provided by ON Semiconductor. "Typical" parameters which may be provided in ON Semiconductor data sheets and/or specifications can and do vary in different applications and actual performance may vary over time. All operating parameters, including "Typicals" must be validated for each customer application by customer's technical experts. ON Semiconductor does not convey any license under its patent rights nor the rights of others. ON Semiconductor products are not designed, intended, or authorized for use as a critical component in life support systems or any FDA Class 3 medical devices or medical devices with a same or similar classification in a foreign jurisdiction or any devices intended for implantation in the human body. Should Buyer purchase or use ON Semiconductor products for any such unintended or unauthorized application, Buyer shall indemnify and hol

PUBLICATION ORDERING INFORMATION

LITERATURE FULFILLMENT:

Literature Distribution Center for ON Semiconductor 19521 E. 32nd Pkwy, Aurora, Colorado 80011 USA Phone: 303-675-2175 or 800-344-3860 Toll Free USA/Canada Fax: 303-675-2176 or 800-344-3867 Toll Free USA/Canada Email: orderlit@onsemi.com N. American Technical Support: 800-282-9855 Toll Free USA/Canada Europe, Middle East and Africa Technical Support: Phone: 421 33 790 2910

Phone: 421 33 790 2910

Japan Customer Focus Center
Phone: 81–3–5817–1050

ON Semiconductor Website: www.onsemi.com

Order Literature: http://www.onsemi.com/orderlit

For additional information, please contact your local Sales Representative